New Jersey Semi-Conductor Products, Inc.

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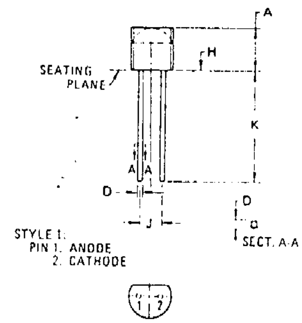
SPRINGFIELD, NEW JERSEY 07081
U.S.A.

MV2101 (SILICON) thru MV2115

VOLTAGE-VARIABLE CAPACITANCE DIODES



DIM	MILLIMETERS MIN	MILLIMETERS MAX	INCHES MIN	INCHES MAX
A	4.45	4.70	0.175	0.185
D	0.41	0.48	0.016	0.019
J	2.29	2.79	0.090	0.110
K	12.70	–	0.500	–

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Reverse Voltage	V_R	30	Volts
Forward Current	I_F	200	mA
Device Dissipation @ T_A = 25°C Derate above 25°C	P_D	280 2.8	mW mW/°C
Junction Temperature	T_J	+125	°C
Storage Temperature Range	T_{stg}	-65 to +150	°C

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic—All Types	Symbol	Min	Typ	Max	Unit
Reverse Breakdown Voltage (I_R = 10 μAdc)	BV_R	30	–	-	Vdc
Reverse Voltage Leakage Current (V_R = 25 Vdc, T_A = 25°C)	I_R	–	–	0.10	μAdc
Series Inductance (f = 250 MHz, Lead Length ≈ 1/16")	L_S	–	6.0	–	nH
Case Capacitance (f = 1.0 MHz, Lead Length ≈ 1/16")	C_C	-	0.18	–	pF
Diode Capacitance Temperature Coefficient (V_R = 4.0 Vdc, f = 1.0 MHz)	TC_C	-	280	400	ppm/°C

	C_T, Diode Capacitance V_R = 4.0 Vdc, f = 1.0 MHz pF			Q, Figure of Merit V_R = 4.0 Vdc, f = 50 MHz	TR, Tuning Ratio C_2/C_{30} f = 1.0 MHz		
Device	Min	Nom	Max	Min	Min	Typ	Max
MV2101	6.1	6.8	7.5	450	2.5	2.7	3.2
MV2102	7.4	8.2	9.0	450	2.5	2.8	3.2
MV2103	9.0	10.0	11.0	400	2.5	2.9	3.2
MV2104	10.8	12.0	13.2	400	2.5	2.9	3.2
MV2105	13.5	15.0	16.5	400	2.5	2.9	3.2
MV2106	16.2	18.0	19.8	350	2.5	2.9	3.2
MV2107	19.8	22.0	24.2	350	2.5	2.9	3.2
MV2108	24.3	27.0	29.7	300	2.5	3.0	3.2
MV2109	29.7	33.0	36.3	200	2.5	3.0	3.2
MV2110	35.1	39.0	42.9	150	2.5	3.0	3.2
MV2111	42.3	47.0	51.7	150	2.5	3.0	3.2
MV2112	50.4	56.0	61.6	150	2.6	3.0	3.3
MV2113	61.2	68.0	74.8	150	2.6	3.0	3.3
MV2114	73.8	82.0	90.2	100	2.6	3.0	3.3
MV2115	90.0	100.0	110.0	100	2.6	3.0	3.3

PARAMETER TEST METHODS

1. L_S, SERIES INDUCTANCE

L_S is measured on a shorted package at 250 MHz using an impedance bridge (Boonton Radio Model 250A RX Meter).

2. C_C, CASE CAPACITANCE

C_C is measured on an open package at 1.0 MHz using a capacitance bridge (Boonton Electronics Model 75A or equivalent).

3. C_T, DIODE CAPACITANCE

(C_T = C_C + C_J). C_T is measured at 1.0 MHz using a capacitance bridge (Boonton Electronics Model 75A or equivalent).

4. TR, TUNING RATIO

TR is the ratio of C_T measured at 2.0 Vdc divided by C_T measured at 30 Vdc.

5. Q, FIGURE OF MERIT

Q is calculated by taking the G and C readings of an admittance bridge at the specified frequency and substituting in the following equations:

$$Q = \frac{2\pi fC}{G}$$

(Boonton Electronics Model 33AS8). Use Lead Length ≈ 1/16".

6. TC_C, DIODE CAPACITANCE TEMPERATURE COEFFICIENT

TC_C is guaranteed by comparing C_T at V_R = 4.0 Vdc, f = 1.0 MHz, T_A = -65°C with C_T at V_R = 4.0 Vdc, f = 1.0 MHz, T_A = +85°C in the following equation which defines TC_C:

$$TC_C = \frac{C_T(+85°C) - C_T(-65°C)}{85 + 65} \cdot \frac{10^6}{C_R(25°C)}$$

Accuracy limited by measurement of C_T to ± 0.1 pF.

Quality Semi-Conductors